

International Rectifier

HEXFET® POWER MOSFET

Provisional Data Sheet No. PD-9.336E

JANTX2N6762
JANTXV2N6762
[REF:MIL-PRF-19500/542]
[GENERIC:IRF430]
N-CHANNEL

500 Volt, 1.5Ω HEXFET

HEXFET technology is the key to International Rectifier's advanced line of power MOSFET transistors. The efficient geometry achieves very low on-state resistance combined with high transconductance.

HEXFET transistors also feature all of the well-established advantages of MOSFETs, such as voltage control, very fast switching, ease of paralleling and electrical parameter temperature stability. They are well-suited for applications such as switching power supplies, motor controls, inverters, choppers, audio amplifiers, and high energy pulse circuits, and virtually any application where high reliability is required.

Product Summary

Part Number	BVDSS	RDS(on)	ID
JANTX2N6768	500V	1.5Ω	4.5A
JANTXV2N6768			

Features:

- Avalanche Energy Rating
- Dynamic dv/dt Rating
- Simple Drive Requirements
- Ease of Paralleling
- Hermetically Sealed

Absolute Maximum Ratings

	Parameter	JANTX2N6762, JANTXV2N6762	Units
ID @ VGS = 10V, TC = 25°C	Continuous Drain Current	4.5	A
ID @ VGS = 10V, TC = 100°C	Continuous Drain Current	3.0	
IMD	Pulsed Drain Current①	18	
PD @ TC = 25°C	Max. Power Dissipation	75	W
	Linear Derating Factor	0.60	W/K ^⑤
VGS	Gate-to-Source Voltage	±20	V
EAS	Single Pulse Avalanche Energy ②	1.1	mJ
IAR	Avalanche Current①	4.5	A
EAR	Repetitive Avalanche Energy①	—	mJ
dv/dt	Peak Diode Recovery dv/dt ③	3.5	V/ns
TJ TSTG	Operating Junction Storage Temperature Range	-55 to 150	°C
	Lead Temperature	300 (0.063 in. (1.6mm) from case for 10.5 seconds)	
	Weight	11.5 (typical)	g

JANTX2N6762, JANTXV2N6762 Device

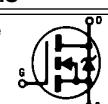
Electrical Characteristics @ $T_j = 25^\circ\text{C}$ (Unless Otherwise Specified)

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	500	—	—	V	$\text{V}_{\text{GS}} = 0\text{V}, \text{I}_D = 1.0\text{ mA}$
$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	Temperature Coefficient of Breakdown Voltage	—	0.78	—	V°C	Reference to 25°C , $\text{I}_D = 1.0\text{ mA}$
RDS(on)	Static Drain-to-Source On-State Resistance	—	—	1.5	Ω	$\text{V}_{\text{GS}} = 10\text{V}, \text{I}_D = 3.0\text{ A}$ ④
		—	—	1.80		$\text{V}_{\text{GS}} = 10\text{V}, \text{I}_D = 4.5\text{ A}$
VGS(th)	Gate Threshold Voltage	2.0	—	4.0	V	$\text{V}_{\text{DS}} = \text{V}_{\text{GS}}, \text{I}_D = 250\mu\text{A}$
g_{fs}	Forward Transconductance	2.7	—	—	S (Ω)	$\text{V}_{\text{DS}} > 15\text{V}, \text{I}_{\text{DS}} = 3.0\text{A}$ ④
IDSS	Zero Gate Voltage Drain Current	—	—	25	μA	$\text{V}_{\text{DS}} = 0.8 \times \text{Max Rating}, \text{V}_{\text{GS}} = 0\text{V}$
		—	—	250		$\text{V}_{\text{DS}} = 0.8 \times \text{Max Rating}$ $\text{V}_{\text{GS}} = 0\text{V}, \text{T}_J = 125^\circ\text{C}$
IGSS	Gate-to-Source Leakage Forward	—	—	100	nA	$\text{V}_{\text{GS}} = 20\text{V}$
IGSS	Gate-to-Source Leakage Reverse	—	—	-100		$\text{V}_{\text{GS}} = -20\text{V}$
Qg	Total Gate Charge	16	—	40	nC	$\text{V}_{\text{GS}} = 10\text{V}, \text{I}_D = 4.5\text{A}$
Qgs	Gate-to-Source Charge	2.0	—	6.0		$\text{V}_{\text{DS}} = \text{Max. Rating} \times 0.5$ see figures 6 and 13
Qgd	Gate-to-Drain ("Miller") Charge	8.0	—	20	ns	$\text{V}_{\text{DD}} = 250\text{V}, \text{I}_D = 4.5\text{A},$ $\text{R}_G = 7.5\Omega, \text{V}_{\text{GS}} = 10\text{V}$ see figure 10
td(on)	Turn-On Delay Time	—	—	30		
tr	Rise Time	—	—	40		
td(off)	Turn-Off Delay Time	—	—	80		
tf	Fall Time	—	—	30	nH	Measured from the drain lead, 6mm (0.25 in.) from package to center of die. Measured from the source lead, 6mm (0.25 in.) from package to source bonding pad.
L _D	Internal Drain Inductance	—	5.0	—		
L _S	Internal Source Inductance	—	13.0	—		
C _{iss}	Input Capacitance	—	610	—	pF	$\text{V}_{\text{GS}} = 0\text{V}, \text{V}_{\text{DS}} = 25\text{V}$ $f = 1.0\text{ MHz}$ see figure 5
C _{oss}	Output Capacitance	—	135	—		
C _{rss}	Reverse Transfer Capacitance	—	65	—		



Source-Drain Diode Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
I _S	Continuous Source Current (Body Diode)	—	—	4.5	A	Modified MOSFET symbol showing the integral reverse p-n junction rectifier.
I _{SM}	Pulse Source Current (Body Diode) ①	—	—	18		
V _{SD}	Diode Forward Voltage	—	—	1.4	V	$\text{T}_j = 25^\circ\text{C}, \text{I}_S = 4.5\text{A}, \text{V}_{\text{GS}} = 0\text{V}$ ④
t _{rr}	Reverse Recovery Time	—	—	900	ns	$\text{T}_j = 25^\circ\text{C}, \text{I}_F = 4.5\text{A}, \text{dI}/\text{dt} \leq 100\text{A}/\mu\text{s}$
QRR	Reverse Recovery Charge	—	—	7.0	μC	$\text{V}_{\text{DD}} \leq 50\text{V}$ ④
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible. Turn-on speed is substantially controlled by L _S + L _D .				



Thermal Resistance

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
R _{thJC}	Junction-to-Case	—	—	1.67	K/W	Typical socket mount
R _{thJA}	Junction-to-Ambient	—	—	30		

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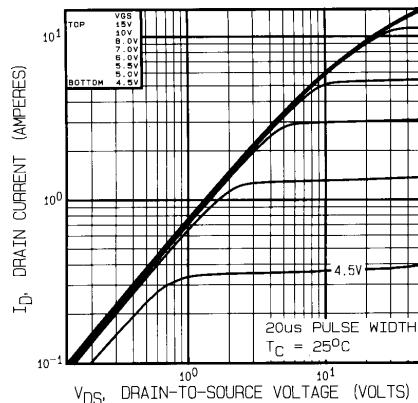


Fig. 1 — Typical Output Characteristics
 $T_c = 25^\circ\text{C}$

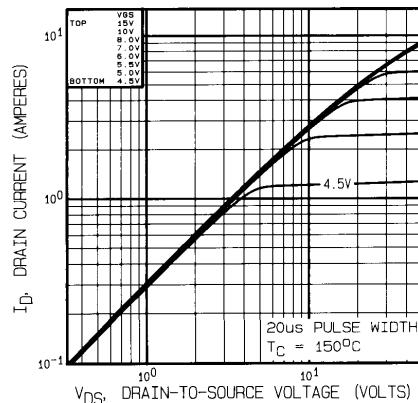


Fig. 2 — Typical Output Characteristics
 $T_c = 150^\circ\text{C}$

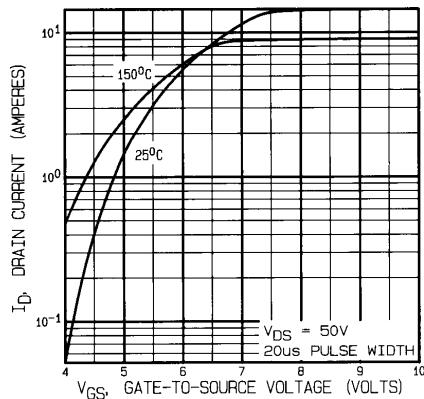


Fig. 3 — Typical Transfer Characteristics

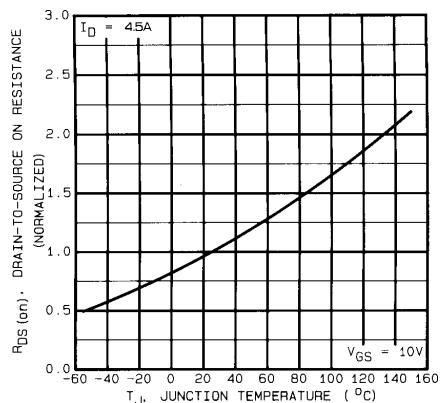


Fig. 4 — Normalized On-Resistance Vs. Temperature

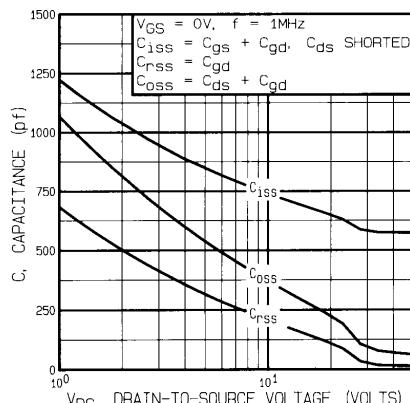


Fig. 5 — Typical Capacitance Vs. Drain-to-Source Voltage

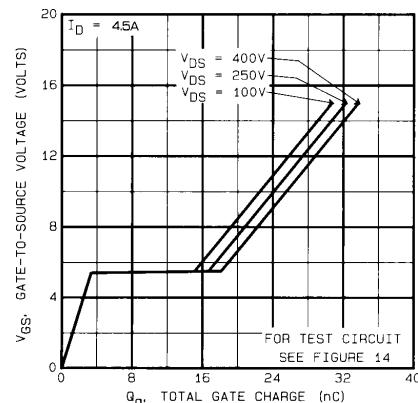


Fig. 6 — Typical Gate Charge Vs. Gate-to-Source Voltage

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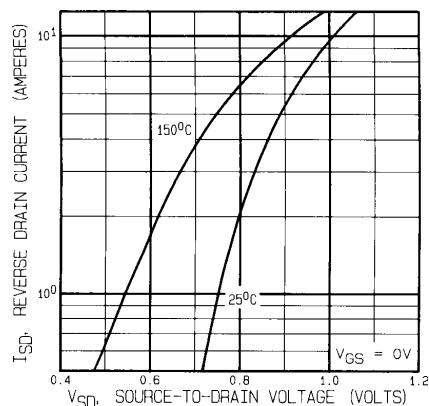


Fig. 7 — Typical Source-to-Drain Diode Forward Voltage

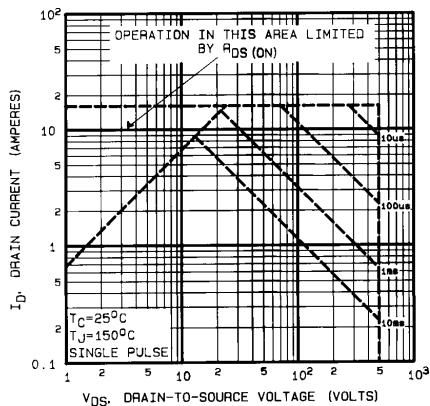


Fig. 8 — Maximum Safe Operating Area

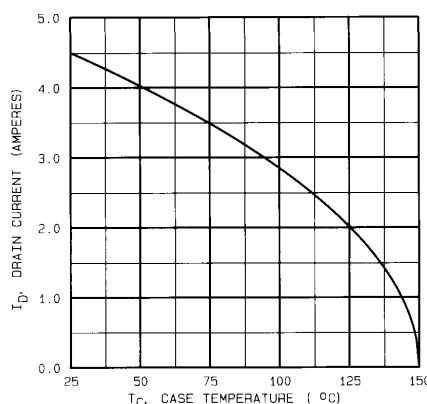


Fig. 9 — Maximum Drain Current Vs. Case Temperature

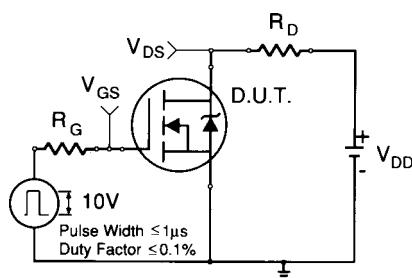


Fig. 10a — Switching Time Test Circuit

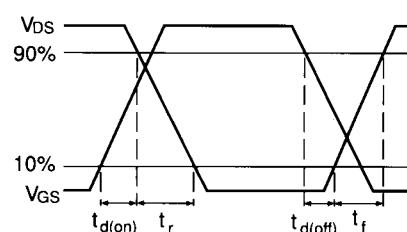


Fig. 10b — Switching Time Waveforms

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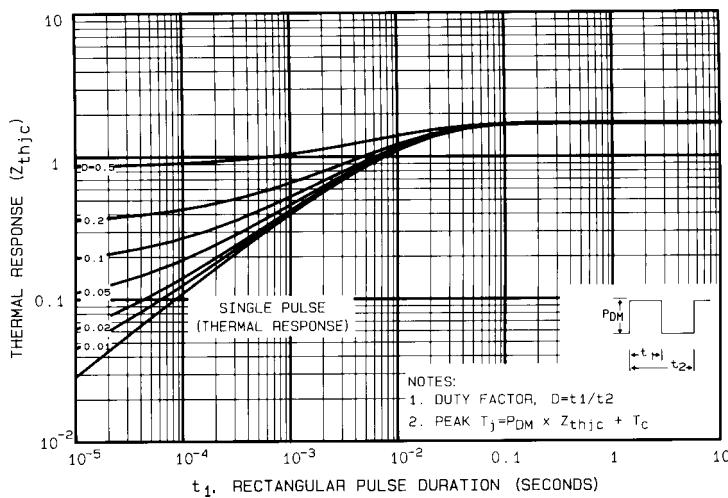


Fig. 11 — Maximum Effective Transient Thermal Impedance, Junction-to-Case Vs. Pulse Duration

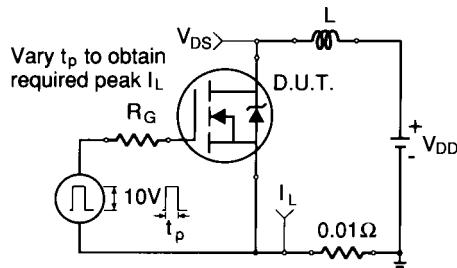


Fig. 12a — Unclamped Inductive Test Circuit

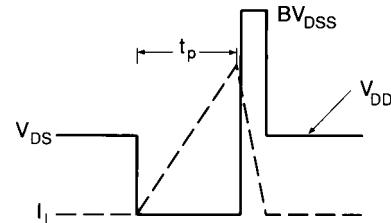


Fig. 12b — Unclamped Inductive Waveforms

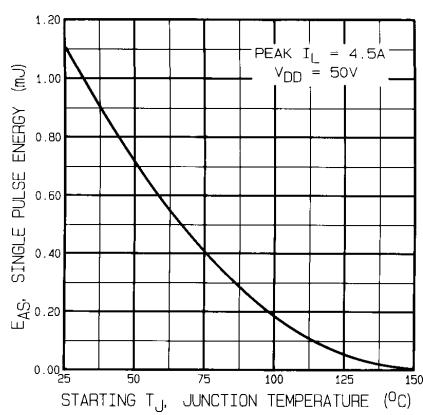


Fig. 12c — Max. Avalanche Energy vs. Current

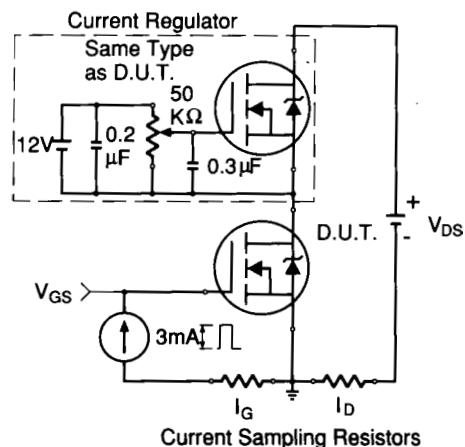
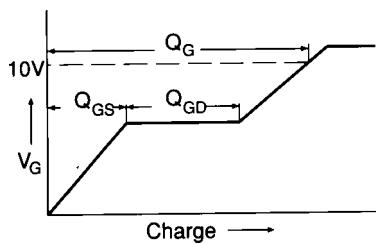


Fig. 13a — Gate Charge Test Circuit

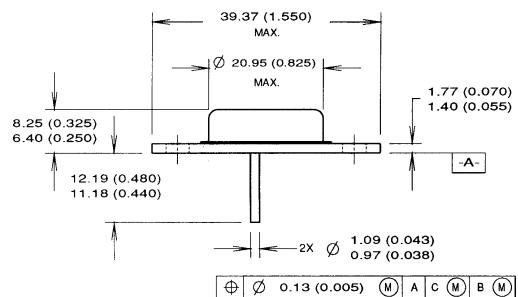
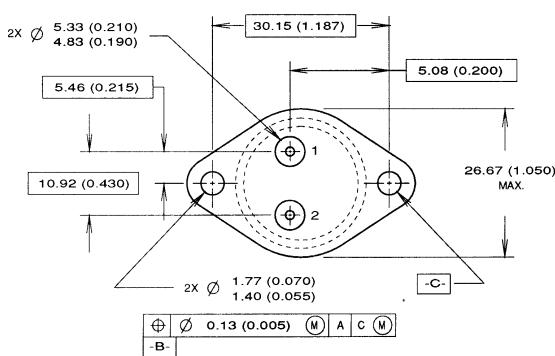
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- ① Repetitive Rating; Pulse width limited by maximum junction temperature.
(see figure 11)
- ② @ $V_{DD} = 50V$, Starting $T_J = 25^\circ C$,
 $EAS = [0.5 * L * (I_L^2) * [BV_{DSS}/(BV_{DSS}-V_{DD})]]$
Peak $I_L = 4.5A$, $V_{GS} = 10V$, $25 \leq R_G \leq 200\Omega$
- ③ $I_{SD} \leq 4.5A$, $dI/dt \leq 75A/\mu s$,
 $V_{DD} \leq BV_{DSS}$, $T_J \leq 150^\circ C$
- ④ Pulse width $\leq 300 \mu s$; Duty Cycle $\leq 2\%$
- ⑤ $K/W = ^\circ C/W$
 $W/K = W/^{\circ}C$

Fig. 13b — Basic Gate Charge Waveform

Case Outline and Dimensions — TO-204AA (Modified TO-3)



All dimensions are shown millimeters (inches)

International
IR Rectifier

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